

Notice of References Cited	Application/Control No. 10/690,538		Applicant(s)/Patent Under Reexamination KLOSTERMANN ET AL.	
	Examiner Samuel M. Heinrich		Art Unit 1725	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,123,781	09-2000	Shimazawa, Kouji	148/108
*	C	US-4,863,877	09-1989	Fan et al.	438/492
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.